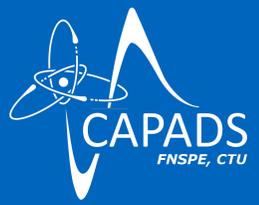


Simulation of Charge Sharing Effects in 70 μm Pixelated CdTe Sensor



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Introduction

- ▶ Pixel detectors becoming an integral part of medical imaging.
- ▶ Current research tends to use CdTe/CdZnTe as gamma-ray sensors due to its high absorption coefficient in the gamma spectrum.
- ▶ To increase spatial resolution of the detector, the pixel pitch has to be reduced.
- ▶ Decreasing size of pixels leads to charge sharing between neighboring pixels.
- ▶ It is important to develop a precise sensor model for characterization of analog front-end amplifiers.

TCAD simulation

- ▶ 3D model of CdTe sensor with Pt cathode and Al/Au pixelated anode was created in TCAD.
- ▶ Sensor was modeled using CdTe material from standard TCAD material library with following parameters:

	Electrons	Holes
Mobility ($\text{cm}^2\text{V}^{-1}\text{s}$)	1100	100
Lifetime (s)	3×10^{-6}	2×10^{-6}

Table 1: Parameters of electrons and holes in CdTe.

- ▶ The pixel pitch was set to 70 μm which corresponds to 55 μm electrode and 15 μm street.
- ▶ The sensor was biased at -1000 V.
- ▶ The Heavylon model was used to generate e-h pairs in the sensor to investigate the sensor response to X-ray photons.
- ▶ The photon interactions were placed at the center of the middle pixel.
- ▶ The interaction depth of each photon was set based on the mean free path, which was calculated by the NIST XCOM software [1].

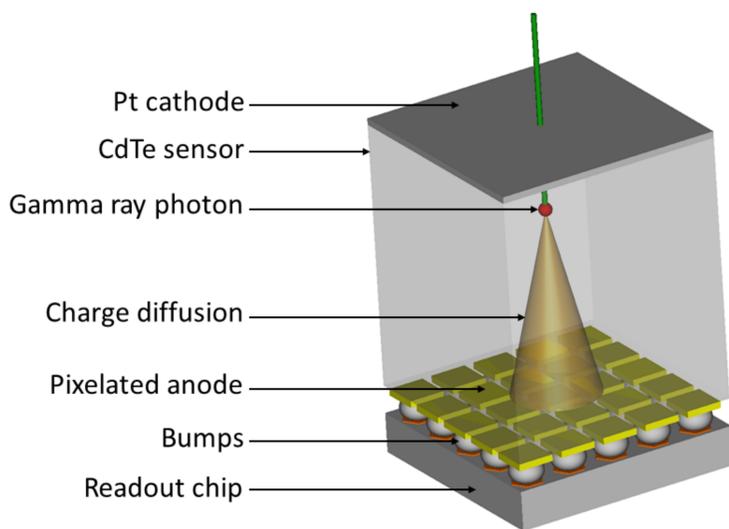


Figure 1: Illustration of a CdTe sensor bump-bonded to a readout chip.

- ▶ The induced signal on the central electrode by drifting e-h can be computed based on the Shockley-Ramo theorem [2].
- ▶ Figure 2. shows the simulation outcome of weighted potential which shows the small pixel effect in pixelated sensor.

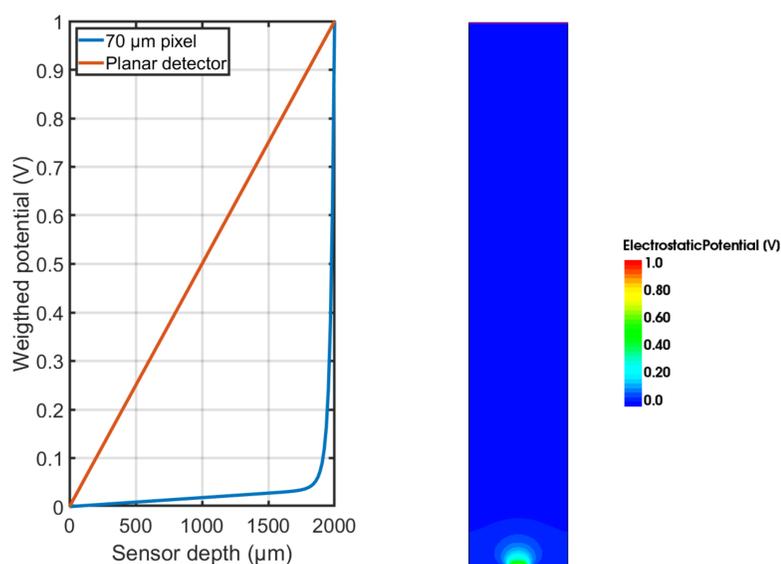


Figure 2: Comparison of weighted potential in planar and pixel detector.

Results

- ▶ Several important parameters of CdTe sensors were studied to create a circuit model of the sensor. The most important are collection time and inter-pixel capacitance.
- ▶ The collection time- t_c and diffusion time- t_d of a 2 mm CdTe sensor for different interaction depths were obtained.

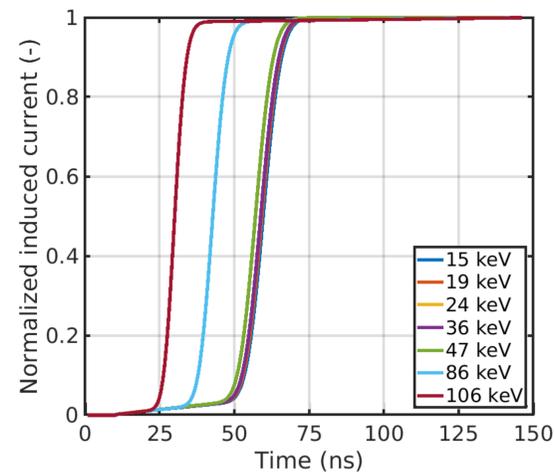


Figure 3: Normalized induced current in central pixel.

Photon E (keV)	t_d (ns)	t_c (ns)
15	49.7	16.9
19	49.2	16.8
24	47.1	16.4
36	48.8	16.8
47	47.0	16.4
86	32.8	13.5
106	20.1	10.4

Table 2: Diffusion and collection time for various photon energies.

- ▶ Based on the t_d a spread of charge between neighboring pixels can be modeled.
- ▶ The charge distribution at collection electrodes can be modeled with Gaussian pulse.
- ▶ Its standard deviation can be found based on Einstein diffusion coefficient and diffusion time:

$$\sigma = \sqrt{2Dt_d}$$

- ▶ The simulation of inter-pixel capacitance was done using AC simulation.
- ▶ Table 2 show the inter pixel capacitance values. C_{1-5} are capacitance between neighboring pixels. C_6 is the capacitance between cathode and central pixel.
- ▶ Based on the simulation outcome the total capacitance is 24.887 fF.

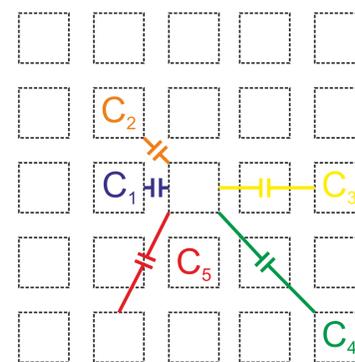


Figure 4: Inter-pixel capacitance schematic diagram.

Capacitance	Occurrence	Value (fF)
C_1	4	4.611
C_2	4	0.778
C_3	4	0.255
C_4	4	0.159
C_5	8	0.203
C_6	1	0.231

Table 3: Interpixel capacitance.

- ▶ The simulation outcome have been used to create a sensor model in verilog-AMS. pixel front-end electronics.

Conclusion

This work has introduced a 3D simulation of pixelated CdTe sensor. The key parameters such as collection time, drift time and pixel capacitance have been obtained. Using the simulation outcome we have created a circuit model which is to be used for development of pixel front-end electronics.

References

- [1] M J Berger, J H Hubbell, S M Seltzer, J Chang, J S Coursey, R Sukumar, and D S Zucker. XCOM: photon cross sections database, 1998.
- [2] Zhong He. Review of the Shockley-Ramo theorem and its application in semiconductor gamma-ray detectors. *Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment*, 463(1-2):250-267, may 2001.

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